



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/834,660
Filing Date April 21, 2001
Inventor Luan C. Tran
Assignee Micron Technology, Inc.
Group Art Unit 2813
Customer No. 021567
Confirmation No. 6625
Examiner Laura Schillinger
Attorney's Docket No. MI22-1637
Customer No. 021567
Title: Semiconductor Processing Methods

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -See Attached Form PTO-1449

The Examiner's attention is directed to the references which are listed on the attached Form PTO-1449, copies of which are attached. No admission is made regarding whether all the submitted references are prior art.

Citation of the referenced art is respectfully requested.

Respectfully submitted,

Dated: _____

5/23/05

By: _____

James D. Shaurette
Reg. No. 39,833

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Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1637SERIAL NO.
09/834,660LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Luan C. TranFILING DATE
April 21, 2001GROUP
2813

U.S. PATENT DOCUMENTS

*Examine r Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,834,019	12/2004	Tran et al.			
	AB	6,734,487	5/2004	Tran et al.			
	AC	6,228,713	5/2001	Pradeep et al.			
	AD	6,501,114	12/2002	Cho et al.			
	AE	6,620,704	9/2003	Miura et al.			
	AF	6,436,751	8/2002	Liou et al.			
	AG	6,770,927	8/2004	Cho et al.			
	AH	2004/0188777 A1	10/2004	Hwang			
	AI	2004/0214355 A1	10/2004	Miura et al.			
	AJ						
	AK						

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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subcla ss	Translation	
							Yes	No
	AL							
	AM							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AN		Van Zant, Peter, "Microchip Fabrication - Third Edition," ©1997, page 332.

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.